Fast Atomic Force Microscopy Imaging using Self-Intersecting Scans and Inpainting

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Outline



- 2 Noise Removal
 - Drift Removal
 - Tilt Removal
 - Streak Detection

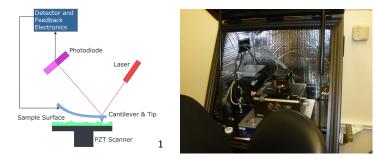


Inpainting

• Penalized Dictionary Inpainting



Atomic Force Microscopy (AFM)



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¹Source: Wikipedia

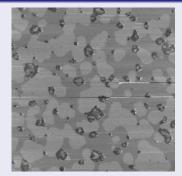
Raster Scan

Raster Scanned Image



 (a) The AFM scans top-down with horizontal scan paths.
 Notice the different mean intensities of each line.

Line-Flattening



(b) Each horizontal scan is line-fitted and the fit is subtracted from the scan line.

Problems with Raster Scan

- Scanning is slow due to resonant frequencies.
- Forces the mean of each line to be the same.
- Distorts image when a dark/light object is on the sides.

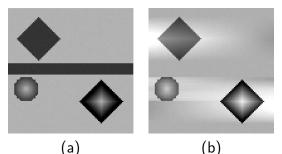
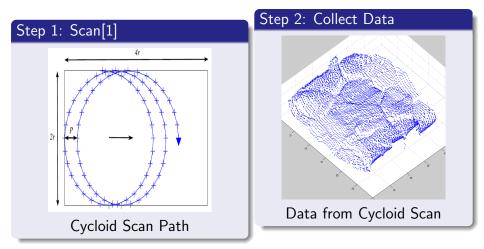


Figure: (a) A simulated image. (b) Line-flattened. Notice the loss of the horizontal bar and the distortion in the foreground and background around objects.

Cycloid Scan



The Cycloid scan was studied as a feasible way to collect data using a "smooth" path.

Model of Distortion

- $\mathsf{S}(\mathsf{t}) = \mathsf{I}(\mathsf{x}(\mathsf{t}),\mathsf{y}(\mathsf{t})) + \mathsf{T}(\mathsf{x}(\mathsf{t}),\mathsf{y}(\mathsf{t})) + \mathsf{D}(\mathsf{t}) + \chi(\mathsf{t}) + \eta(\mathsf{t})$
 - S: Signal from AFM.
 - I: Height of sample function of bounded variation.
 - T: Tilt approximately a plane in x and y.
 - D: Drift continuous function with small second derivative.
 - χ : Streaks simple function of finite discontinuity.

• η : Gaussian noise.

Poly-Flattening

Subtract polynomial fit from scan arcs in analogue with line-flattening.

Issues:

• Assumes mean is constant across flattening interval.

- Does not enforce continuity between arcs.
- Is multi-valued in intersections.
- Distorts image when there is a high contrast.

Difference-Flattening

We can exploit self-intersections on the scan path. If (x(a), y(a)) = (x(b), y(b)) then $\Delta_i = S(b_i) - S(a_i) = D(b_i) - D(a_i)$ (ignoring χ and η). Let ℓ be the number of intersections.

Poly-Difference-Flattening

- Approximate D(t) by an *n*-degree polynomial $\tilde{D}(t) = \sum_{k=1}^{n} \alpha_k \phi_k(t)$ where $\phi_k(t) = t^k$.
- For simplicity, represent $\alpha = [\alpha_1 \alpha_2 \cdots \alpha_n]^T$.
- Using least squares, we minimize $E = \sum_{i=1}^{\ell} (\tilde{D}(b_i) \tilde{D}(a_i) \Delta_i)^2.$
- We simplify the process by introducing a general basis for the related function

$$\mathfrak{d}(a_i, b_i) = \tilde{D}(a_i) - \tilde{D}(b_i) = \sum_{k=1}^n \alpha_k (\phi_k(t_1) - \phi_k(t_2))$$
$$= \sum_{k=1}^n \alpha_k \Phi_k = [\Phi_1(a_i, b_i) \Phi_2(a_i, b_i) \dots \Phi_n(a_i, b_i)] \alpha$$

Poly-Difference-Flattening

• Since
$$E = \|\Delta - \Phi\alpha\|^2$$
,
 $\frac{\partial E}{\partial \alpha} = 2\Phi^T \Phi \alpha - 2\Phi^T \Delta = 0$ gives
 $\Phi^T \Phi \alpha = \Phi^T \Delta$

where given the *i*th intersection, a_i is the first visit to an intersection, b_i is the second visit and $\Phi = [(b_i)^j - (a_i)^j]_{ij}$.

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Poly-Difference-Flattening

Benefits:

- Takes into account the intersections.
- Enforces continuity between arcs.
- Preserves shades, i.e. does not have line-flattening distortions.
- Produces better results than Poly-Flattening.

Issues:

- The polynomial requires a high degree for fitting severe thermal drift; this causes numerical instability.
- "Blows up" at the ends.

Trig-Difference-Flattening

Same idea as poly differences, but using $\{e^{ikx}\}_{0 < |k| \le n}$ for our basis and $\Phi = [e^{\sqrt{-1}jb_i} - e^{\sqrt{-1}jb_i}]_{ij}$. Benefits:

- Takes into account the intersections.
- Fits the boundedness and oscillation of Tilt and Drift better than Poly-Flattening.

Issues:

- Slower than the previous drift removal methods.
- The trig functions require a high degree for fitting severe thermal drift; this causes numerical instability.

Smoothing Spline over Differences

- For splines, $E = LSQ + \lambda Penalty$ where LSQ is the least squares term and Penalty is a penalty term for "waviness" of the spline.
- Arbitrary splines can be constructed with a basis of B-splines:

$$\begin{array}{lll} \mathsf{N}_{i,0}(t) & = & \begin{cases} 1 & t_i \leq t < t_{i+1} \\ 0 & \text{otherwise} \end{cases} & (\mathsf{Base \ case}) \\ \mathsf{N}_{i,j}(t) & = & \frac{t-t_i}{t_{i+j}-t_i} \mathsf{N}_{i,j-1}(t) + \frac{t_{i+j+1}-t}{t_{i+j+1}-t_{i+1}} \mathsf{N}_{i+1,j-1}(t) \end{array}$$

where j is the degree of the spline polynomial and $1 \le i \le m - 1 - j$ with m being the number of knots.

Smoothing Spline over Differences

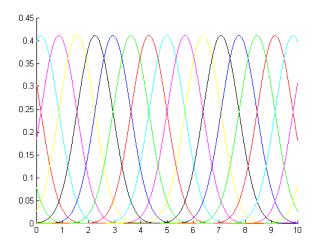


Figure: An example of a spline basis

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Smoothing Spline over Differences

•
$$\mathsf{LSQ} = \| \Phi \alpha - \Delta \|^2$$
 and

Penalty =
$$\int_0^T \|\Phi''\alpha\|^2 dt$$

= $\alpha^T \left(\int_0^T \Phi''^T \Phi'' dt\right) \alpha$
= $\alpha^T M\alpha$ where T is the ending time.

• The functional is then

$$E = \|\Phi\alpha - \Delta\|^2 + \lambda \alpha^T M\alpha$$
$$0 = \frac{\partial E}{\partial \alpha} = 2\Phi^T \Phi\alpha + 2\Phi^T \Delta - 2\lambda M\alpha$$
$$\Phi^T \Delta = \lambda M\alpha - \Phi^T \Phi\alpha$$

Smoothing Spline over Differences

Benefits:

- Takes into account the intersections.
- Fits the boundedness and oscillation of tilt and drift better than Poly-Flattening.

• Does not require a high degree to work well.

Issue:

• Requires a recursively defined basis.

Tilt Removal

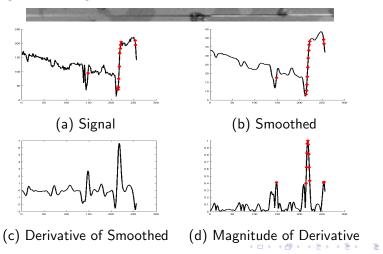


After drift is removed, a plane is fitted to the image and subtracted off.

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Streak Detection

A threshold is used to mark the locations of the smoothed signal with high derivative. This then marks the streaks.



Streak Detection

Issues:

- A threshold must be found.
- Conservative thresholds have too many false positives.

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• Cannot be used alone to remove streaks.

Double Archimedean Spiral Scan

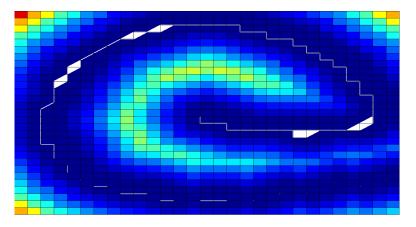
The problem of finding a curve ϕ that covers the most space can be written as an energy minimization:

$$E(\phi) = \int_{\Omega} \min_{t} d(z, \phi(t)) dz$$

with ϕ having fixed length L > 0 and $d(\cdot, \cdot)$ being L^2 distance.

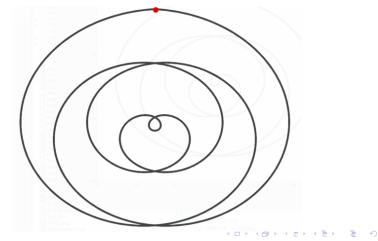
Double Archimedean Spiral Scan

The expression min $d(z, \phi(t))$ can be best visualized as a heat map. Running simulated annealing on Matlab, we get:



Double Archimedean Spiral Scan

The image suggests a path similar to an Archimedean Spiral. To be able to remove drift, intersections are needed, so a Double Archimedean Spiral Scan is used:



Cycloid vs. Double Archimedean Spiral

Benefit of Double Archimedean Spiral over Cycloid:

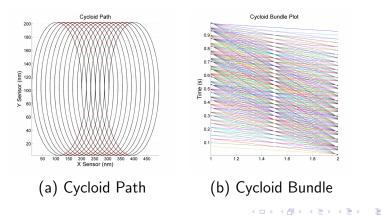
• The Archimedean Spiral fits the Energy functional $E(\phi) = \int_{\Omega} \min_{t} d(z, \phi(t)) dz$ better than Cycloid. Hence, it covers more space than Cycloid for the same length of the curve.

Benefit of Cycloid over Double Archimedean Spiral:

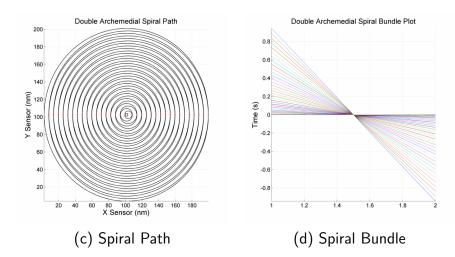
• The Cycloid scan has short-term and long-term self-intersections in regular intervals which facilitates good drift removal.

Cycloid vs. Double Archimedean Spiral

Each connecting line represents a temporal connection between intersections. A connection which starts from the right is when the scan hits the intersection and the left indicates when it is revisited.



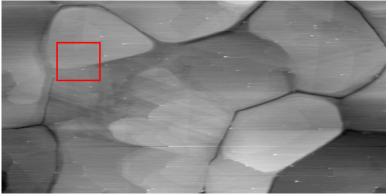
Cycloid vs. Double Archimedean Spiral



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Penalized Dictionary Inpainting

Given image I, associate with it a neighborhood matrix $B = [\vec{B_1} \cdots \vec{B_\ell}]^T$, where each $\vec{B_i}$ is a column vector representation of a neighborhood box.



Penalized Dictionary Inpainting

Assume there is a dictionary which succinctly describes these neighborhoods. Then we can write $\tilde{B} = PV$ where P are the coefficients, V is the dictionary, and \tilde{B} approximates B. Then we can minimize the least squares error to simultaneously solve for P and V:

$$E = \|B - PV\|^2$$

$$\frac{\partial E}{\partial P} = -2(B - PV)V^{T}$$
$$\frac{\partial E}{\partial V} = -2P^{T}(B - PV)$$

Gradient descent gives,

$$P_{k+1} = P_k + \tau (B - P_k V_k) V_k^T$$
$$V_{k+1} = V_k + \tau P_k^T (B - P_k V_k)$$

Notice that in the case of inpainting the difference B - PV is taken only on known data.

Penalized Dictionary Inpainting

However, this formulation does not enforce a geometric constraint. To regularize it, we include a penalty term. We require adjacent neighborhoods' dictionary basis expression to be similar, i.e. if $B_i = P_i V$ is adjacent to $B_j = P_j V$ then $||P_i - P_j||^2$ is small. This corresponds to a high dimensional derivative and is analogous to

Heat equation inpainting.

Combined, these arrive at the evolution:

$$egin{aligned} & P_{k+1} = P_k + au(B - P_k V_k) V_k^T - \lambda M P_k \ & V_{k+1} = V_k + au P_k^T (B - P_k V_k) \end{aligned}$$

Penalized Dictionary Inpainting

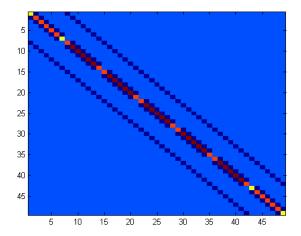


Figure: Banded Matrix M

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GUI

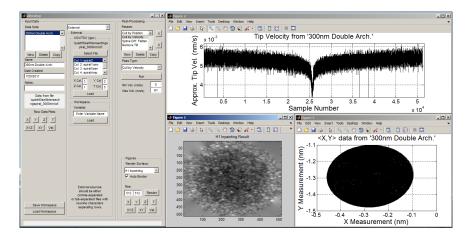
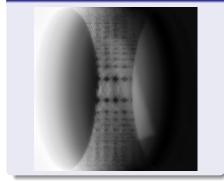


Figure: Afmshop

Results: Cycloid Scan

TV Inpainting without Drift Removal



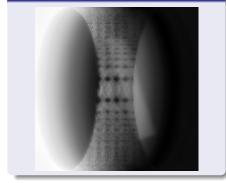
TV Inpainting with Poly-Flattening



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Results: Cycloid Scan

TV Inpainting without Drift Removal



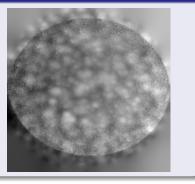
TV Inpainting with Spline Drift Removal



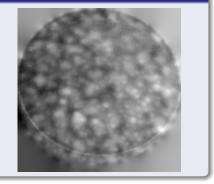
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Results: Double Archimedean Spiral Scan Courtesy of Lawrence Berkeley Laboratory

TV Inpainting without Drift Removal



TV Inpainting with Spline Drift Removal



Results: Penalized Dictionary Inpainting

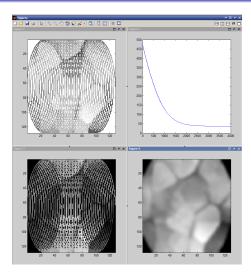


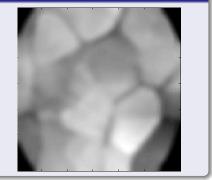
Figure: An example of Penalized Dictionary Inpainting

Results: Penalized Dictionary Inpainting

TV Inpainting



Penalized Dictionary Inpainting



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Future Work

- Automate/Improve Streak Detection.
- Investigate other scan paths.
- Incorporate different regularization into penalized dictionary inpainting.
- Extend our inpainting method to include multi-resolution considerations.

• Finalize a GUI that can be used on actual AFM data.

Acknowledgements



Paul Ashby

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Y.K Yong, Moheimani.S.O.R., and I.R. Petersen. High-speed cycloid-scan atomic force microscopy. *Nanotechnology*, 2010.

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